

IAP20 Rec'd PCT/PTO 04 MAY 2006

INFORMATION DISCLOSURE STATEMENT

Applicant : Washio et al.
 App. No : Unknown
 Filed : Filed Herewith
 For : THICK FILM PHOTORESIST
 COMPOSITION AND METHOD OF
 FORMING RESIST PATTERN
 Examiner : Unassigned
 Art Unit : Unknown

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

May 4, 2006

(Date)

Neil S. Bartfeld, Ph.D., Reg. No. 39,901

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application is a PTO/SB/08 Equivalent listing 3 references to be considered by the Examiner. Also enclosed is 1 foreign patent reference and/or non-patent literature as listed on the Information Disclosure Statement.

This Information Disclosure Statement is being filed within three months of the filing date, with an RCE or before receipt of a first office action after an RCE and no fee is required.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: May 4, 2006

By: 
 Neil S. Bartfeld, Ph.D.
 Registration No. 39,901
 Agent of Record
 Customer No. 20,995
 (619) 235-8550

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application No.	Unknown
		Filing Date	Filed Herewith 10/578398
		First Named Inventor	Yasushi Washio
		Art Unit	Unknown
(Multiple sheets used when necessary)		Examiner	Unassigned
SHEET 1 OF 1		Attorney Docket No.	SHIGA7.049APC

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	2003/0059706 A1	03-27-2003	Misumi et al.	
	2	5,965,328	10-12-1999	Sano et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	3	JP 08-078318	03-22-1996	Naito Makiko	T ¹ Abstract

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Examiner Signature	Date Considered
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	

¹ - Place a check mark in this area when an English language Translation is attached.